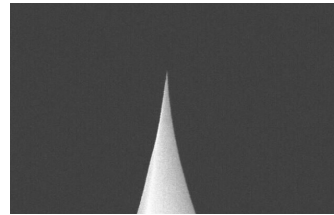


FORT-SS

FORT-SS probes are Super-Sharp silicon probes designed for Force Modulation applications. These probes have a medium frequency and spring constant that make them ideally suited to Force Modulation Microscopy. Our Super Sharp probes yield enhanced resolution images.

Tip Specifications

- **Material:** Silicon
- **Shape:** Pyramidal
- **Height (μm):** 14-16
- **Aspect ratio:** >3.5
- **ROC (nm) :** 2
- **Coating:** None



FORT-SS

On click zoom images

[Download Spec](#)

Cantilever Specifications

Material: Silicon

Shape :Rectangular

Reflex
coating :None

| Parameter | Nominal | Min | Max |
|-----------------------------|---------|-------|-------|
| k (N/m) | 1.6 | 0.6 | 3.7 |
| f (kHz) | 61.0 | 43.0 | 81.0 |
| Length (μm) | 225.0 | 215.0 | 235.0 |
| Width (μm) | 27.0 | 22.0 | 32.0 |
| Thickness (μm) | 2.70 | 2.20 | 3.20 |